

## Features

- Dual RF input for antenna space and frequency diversity, LNA cascading or differential feeding
- Fully integrated PLL-based synthesizer
- $\square$  2<sup>nd</sup> mixer with image rejection
- **D** Reception of ASK or FSK modulated signals
- □ Wide operating voltage and temperature ranges
- Very low standby current consumption
- □ Low operating current consumption
- External IF filters 455kHz or 10.7MHz
- □ Internal FSK demodulator
- □ Average or peak detection data slicer mode
- RSSI output with high dynamic range for RF level indication
- Output noise cancellation filter
- □ MCU clock output
- □ High over-all frequency accuracy
- □ 32-pin Quad Flat No-Lead Package (QFN)

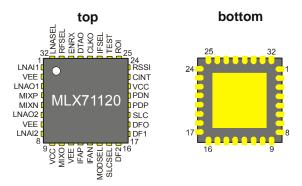
## **Ordering Information**

Part Number	Temperature Code	Package Code	Delivery Form
MLX71120	K (-40 °C to 125 °C)	LQ (32 L QFN 5x5 Quad)	73 pc/tube 5000 pc/T&R

## Application Examples

- General digital and analog RF receivers at 300 to 930MHz
- □ Tire pressure monitoring systems (TPMS)
- Remote keyless entry (RKE)
- □ Low power telemetry systems
- □ Alarm and security systems
- Active RFID tags
- **D** Remote controls
- Garage door openers
- Home and building automation

## **Pin Description**



## **General Description**

The MLX71120 is a multi-band, single-channel/dual-channel RF receiver based on a double-conversion super-heterodyne architecture. It can receive FSK and ASK modulated signals. The IC is designed for general purpose applications for example in the European bands at 433MHz and 868MHz or for similar applications in North America or Asia, e.g. at 315MHz or 915MHz. It is also well-suited for narrow-band applications according to the ARIB STD-T67 standard in the frequency range 426MHz to 470MHz.

The receiver's extended temperature and supply voltage ranges make the device a perfect fit for automotive or similar applications where harsh environmental conditions are expected.



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## 1 Theory of Operation

### 1.1 General

The MLX71120 receiver architecture is based on a double-conversion super-heterodyne approach. The two LO signals are derived from an on-chip integer-N PLL frequency synthesizer. The PLL reference frequency is derived from a crystal (XTAL). As the first intermediate frequency (IF1) is very high, a reasonably high degree of image rejection is provided even without using an RF front-end filter. At applications asking for very high image rejections, cost-efficient RF front-end filtering can be realized by using a SAW filter in front of the LNA. The second mixer MIX2 is an image-reject mixer.

The receiver signal chain is setup by one (or two) low noise amplifier(s) (LNA1, LNA2), two down-conversion mixers (MIX1, MIX2) and an external IF filter with an on-chip amplifier (IFA). By choosing the required modulation via an FSK/ASK switch (at pin MODSEL), either the on-chip FSK demodulator (FSK DEMOD) or the RSSI-based ASK detector is selected. A second order data filter (OA1) and a data slicer (OA2) follow the demodulator. The data slicer threshold can be generated from the mean-value of the data stream or by means of the positive and negative peak detectors (PKDET+/-). A digital post-processing of the sliced data signal can be performed by a noise cancellation filter (NCF) building block.

The dual LNA configuration can be used for antenna space diversity or antenna frequency diversity or to setup an LNA cascade (to further improve the input sensitivity). The two LNAs can also be setup to feed the RF signal differentially.

A sequencer circuit (SEQ) controls the timing during start-up. This is to reduce start-up time and to minimize power dissipation.

A clock output, which is a divide-by-8 version of the crystal oscillator signal, can be used to drive a microcontroller. The clock output is open drain and gets activated through a load connected to positive supply.

#### 1.2 Technical Data Overview

- Input frequency ranges: 300 to 470MHz 610 to 930MHz
- D Power supply range: 2.1 to 5.5V
- Temperature range: -40 to +125°C
- □ Shutdown current: 50 nA
- Operating current: 6.5 to 8.1mA
- FSK input sensitivity: -108dBm\* (WB, 433MHz) -112dBm\* (NB, 433MHz)
- □ ASK input sensitivity: -113dBm\* (WB, 433MHz)
- Selectable IF2 frequency: 10.7MHz or 455kHz
- FSK deviation range: ±10kHz to ±100kHz (WB) ±2kHz to ±10kHz (NB)
- Image rejection:
  65dB 1<sup>st</sup> IF (with external RF front-end filter)
  25dB 2<sup>nd</sup> IF (internal image rejection)
- Maximum data rate: 50kps RZ (bi-phase) code, 100kps NRZ
- □ Spurious emission: < -54dBm
- □ Linear RSSI range: > 70dB
- Crystal reference frequency: 16 to 27MHz
- □ MCU clock frequency: 2.0 to 3.4MHz

\* at 4kbps NRZ, BER = 3.10<sup>-3</sup>, without SAW front-end-filter loss

WB – wideband (180kHz bandwidth at IF2=10.7MHz) NB – narrowband (20kHz bandwidth at IF2=455kHz)



## 1.3 Block Diagram

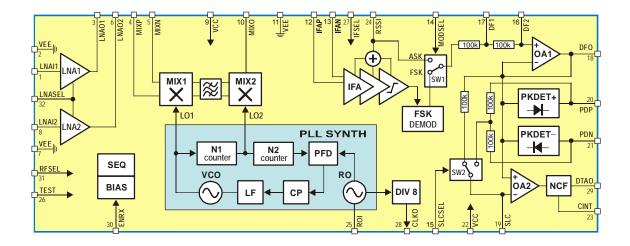


Fig. 1: MLX71120 block diagram

The MLX71120 receiver IC consists of the following building blocks:

- PLL synthesizer (PLL SYNTH) to generate the first and second local oscillator signals LO1 and LO2. The PLL SYNTH consists of a fully integrated voltage-controlled oscillator (VCO), a distributed feedback divider chain (N1,N2), a phase-frequency detector (PFD) a charge pump (CP), a loop filter (LF) and a crystal-based reference oscillator (RO).
- Two low-noise amplifiers (LNA1, LNA2) for high-sensitivity RF signal reception
- First mixer (MIX1) for down-conversion of the RF signal to the first IF (intermediate frequency)
- Second mixer (MIX2) with image rejection for down-conversion from the first to the second IF
- IF amplifier (IFA) to provide a high voltage gain and an RSSI signal output
- FSK demodulator (FSK DEMOD)
- Operational amplifiers OA1 and OA2 for low-pass filtering and data slicing, respectively
- Positive (PKDET+) and negative (PKDET-) peak detectors
- Switches SW1 to select between FSK and ASK as well as SW2 to chose between averaging or peak detection mode.
- Noise cancellation filter (NCF)
- Sequencer circuit (SEQ) and biasing (BIAS) circuit
- Clock output (DIV8)



## 1.4 Operating Modes

The receiver offers two operating modes selectable by setting the corresponding logic level at pin ENRX.

ENRX	Description	
0	Shutdown mode	
1	Receive mode	

**Note:** ENRX is pulled down internally.

The receiver's start-up procedure is controlled by a sequencer circuit. It performs the sequential activation of the different building blocks. It also initiates the pre-charging of the data filter and data slicer capacitors in order to reduce the overall start-up time and current consumption during the start-up phase.

At ENRX = 0, the receiver is in shutdown mode and draws only a few nÅ. The bias system and the reference oscillator are activated after enabling the receiver by a positive edge at pin ENRX. The crystal oscillator (RO) is turned on first. Then the crystal oscillation amplitude builds up from noise. After reaching a certain amplitude level at pin ROI, the whole IC is activated and draws the full receive mode current consumption  $I_{CC}$ . This event is used to start the pre-charging of the external data path capacitors. Pre-charging is finished after 5504 clock cycles. After that time the data output pin DTAO output is activated.

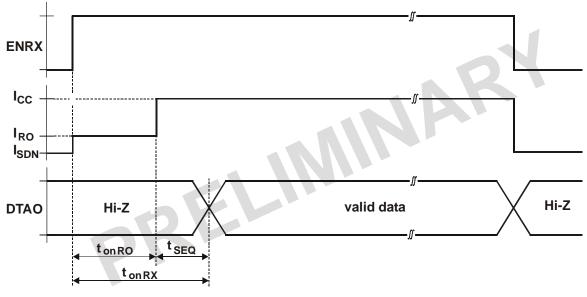


Fig. 2: Timing diagram of start-up and shutdown behavior

### 1.5 LNA Selection

The receiver features two identical LNAs. Each LNA is a cascode amplifier with a voltage gain of approximately 18dB. The actual gain depends on the antenna matching network at the inputs and the LC tank network between the LNA outputs and mixer input. LNA operation can be controlled by the LNASEL pin.

LNASEL	Description	
0	LNA1 active, LNA2 shutdown	
Hi-Z	LNA1 and LNA2 active	
1	LNA1 shutdown, LNA2 active	

Pin LNASEL is internally pulled to VCC/2 during receive mode. Therefore both LNAs are active if LNASEL is left floating (Hi-Z state).



## 1.6 Mixer Section

The mixer section consists of two mixers. Both are double-balanced mixers. The second mixer is built as an image rejection mixer. The first mixer's inputs (MIXP and MIXN) are functionally the same. For single-ended drive, the unused input has to be tied to ground via a capacitor. A soft band-pass filter is placed between the mixers.

RFSEL	Description		
0	Input frequency range 300 to 470MHz		
1	Input frequency range 610 to 930MHz		

Pin RFSEL is used to select the required RF band. The LO frequencies and the proper sidebands for image suppression will be set accordingly. The mixer output (MIXO) is to drive an external IF filter. This output is set up by a source follower that can be biased to create a driving impedance of either 1500 Ohms or 330 Ohms, depending on the logic level at pin IFSEL.

IFSEL	Description	
0	IF2 = 455 kHz	
1	IF2 = 10.7 MHz	

This feature allows to use standard ceramic filters for 455kHz and 10.7MHz. They can be connected directly without additional matching elements. The overall voltage conversion gain of the mixer section is approximately 25dB.

## 1.7 IF Amplifier

After having passed the IF filter, the signal is amplified by a high-gain limiting amplifier. It consists of several AC-coupled gain stages with a bandwidth of 400kHz to 11MHz. The overall small-signal pass-band gain is about 80dB. A received-signal-strength indicator (RSSI) signal is generated within the IF amplifier and is available at pin RSSI.

### 1.8 PLL Synthesizer

The PLL synthesizer consists of a fully integrated voltage-controlled oscillator running at 400MHz to 640MHz, a distributed feedback divider chain, an edge-triggered phase-frequency detector, a charge pump, a loop filter and a crystal-based reference oscillator. The PLL is used for generating the LO signals. The LO1 is directly taken from the VCO output, and the LO2 is derived from the LO1 signal passing the N1 counter. Another counter N2 follows N1. The overall feedback divider ratio N<sub>tot</sub> is fixed to 24. The values of N1 and N2 are depending on the selected RF band that can be chosen via pin RFSEL.

RFSEL	f <sub>LO1min</sub> [MHz]	f <sub>LO1max</sub> [MHz]	f <sub>LO2min</sub> [MHz]	f <sub>LO2max</sub> [MHz]	N <sub>1</sub>	N <sub>2</sub>	N <sub>tot</sub>
0	400	640	100	160	4	6	24
1	400	640	200	320	2	12	24



### 1.9 Reference Oscillator

A Colpitts crystal oscillator with integrated functional capacitors is used as the reference oscillator (RO) of the PLL synthesizer. The equivalent input capacitance CRO offered to the crystal at pin ROI is about 18pF. The crystal oscillator features an amplitude control loop. This is to assure a very stable frequency over the specified supply voltage and temperature range together with a short start-up time. A buffer amplifier with hysteresis is between RO and PFD. Also a clock divider follows the buffer.

### 1.10 Clock Output

The clock output pin CKOUT is an open-drain output. For power saving reasons, the circuit is only active if an external pull-up resistor RCL is applied to the pin. Furthermore, RCL can be used to adjust the clock waveform. It forms an RC low-pass together with the capacitive load at the pin, the parasitics of the PCB and the input capacitance of the external circuitry (e.g. a microcontroller).

The clock output feature is disabled if pin CKOUT is connected to ground or left open.

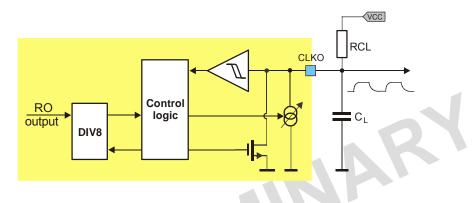


Fig. 3: Clock output implementation

### 1.11 FSK Demodulator

The integrated FSK demodulator is based on a phase-coincidence demodulator principle. An injectionlocked oscillator (ILO) is used as a frequency-dependent phase shifter. This topology features a good linearity of the frequency-phase relationship over the entire locking range. The type of demodulator has no built-in constraints regarding the modulation index. It also offers a wide carrier acceptance range.

In addition, the demodulator provides an AFC loop for correcting the remaining free-running frequency error and drift effects, and also to remove possible frequency offsets between transmitter and receiver frequencies. The AFC loop features a dead band which means that the AFC loop is only closed if the demodulator output voltage leaves the linear region of the demodulator. Most of the time, the control loop is open. This leads to several advantages. The AFC loop bandwidth can be high and therefore the reaction time is short. Furthermore the demodulator itself has no low-end cut-off frequency.

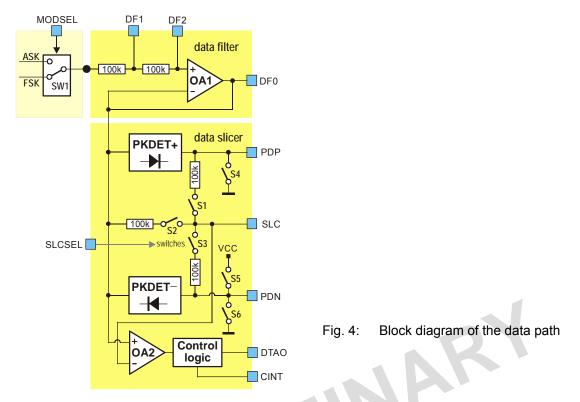
The FSK demodulator has a negative control slope, this means the output voltage decreases by increasing the IF2 frequency. This guarantees an overall positive slope because the mixer section converts the receive frequency to IF2 either with high-low or low-high side injection.

The FSK demodulator is turned off during ASK demodulation.



### 1.12 Baseband Data Path

The baseband data path can be divided into a data filter section and a data slicer section.



The data filter input is either connected to the ASK or to the FSK demodulation output. Pin MODSEL can be used to set the internal switch SW1 accordingly.

MODSEL	Description		
0	ASK demodulation		
1	FSK demodulation		

For ASK demodulation, the RSSI signal of the IFA is used. During FSK demodulation, SW1 is connected to the FSK demodulator output.

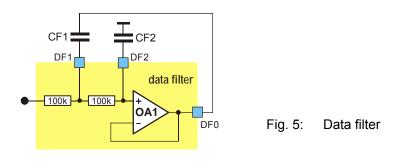
The SLCSEL pin is used to control the internal switches depending on operating and slicer mode.

Pins DF1, DF2, DFO, SLC and DTAO are left floating during shutdown mode. So they are in a high-Z state.



## 1.13 Data Filter

The data filter is formed by the operational amplifier OA1, two internal  $100k\Omega$  resistors and two external capacitors. It is implemented as a 2<sup>nd</sup> order Sallen-Key filter. The low pass filter characteristic rejects noise at higher frequencies and therefore leads to an increased sensitivity.



The filter's pole locations can be set by the external capacitors CF1 and CF2. The cut-off frequency  $f_c$  has to be adjusted according to the transmission data rate R. It should be set to approximately 1.5 times the fastest expected data rate. For a Butterworth filter characteristic, the data filter capacitors can be calculated as follows.

$$CF1 = \frac{1}{\sqrt{2} \cdot \pi \cdot 100k \cdot f_c} \qquad CF2 = \frac{CF1}{2}$$

R <sub>RZ</sub> [kbit/s]	R <sub>NRZ</sub> [kbit/s]	fc [kHz]	CF1 [pF]	CF2 [pF]
0.6	1.2	0.9	2200	1000
1.2	2.4	1.8	1200	680
1.6	3.2	2.4	1000	470
2.4	4.8	3.6	680	330
3.3	6.6	5	470	220
4.8	9.6	7.2	330	150
6.0	12	9	220	100

## 1.14 Data Slicer

The purpose of the data slicer is to convert the filtered data signal into a digital output. It can therefore be considered as an analog-to-digital converter. This is done by using the operational amplifier OA2 as a comparator that compares the data filter output with a threshold voltage. The threshold voltage can be derived in two different ways from the data signal.

SLCSEL	Description		
0	Averaging detection mode		
1	Peak detection mode		



### 1.14.1 Averaging Detection Mode

The simplest configuration is the averaging or RC integration method. Here an on-chip  $100k\Omega$  resistor together with an external slicer capacitor (CSL) are forming an RC low-pass filter. This way the threshold voltage automatically adjusts to the mean or average value of the analog input voltage.

To create a stable threshold voltage, the cut-off frequency of the low pass has to be lower than the lowest signal frequency.

$$CSL \ge \frac{\tau_{AVG}}{100k} \qquad \qquad \tau_{AVG} = \frac{1.5}{R_{RZ}}$$

A long string of zeros or ones, like in NRZ codes, can cause a drift of the threshold. That's why a Manchester or other DC-free coding scheme works best.

The peak detectors are disabled during averaging detection mode, and the output pins PDP and PDN are pulled to ground (S4, S6 are closed).

#### 1.14.2 Peak Detection Mode

Peak detection mode has a general advantage over averaging detection mode because of the part attack and slow release times. Peak detection should be used for all non DC-free codes like NRZ. In this configuration the threshold is generated by using the positive and negative peak detectors. The slicer comparator threshold is set to the midpoint between the high output and the low output of the data filter by an on-chip resistance divider. Two external capacitors (CP1, CP2) determine the release times for the positive and negative envelope. The two on-chip resistors provide a path for the capacitors to discharge. This allows the peak detectors to dynamically follow peak changes of the data filter output voltage. The attack times are very short due to the high peak detector load currents of about 500uA.

The decay time constant mainly depends on the longest time period without bit polarity change. This corresponds to the maximum number of consecutive bits with the same polarity ( $N_{MAX}$ ).

$$CP1/2 \ge \frac{\tau_{\text{DECAY}}}{100k} \qquad \qquad \tau_{\text{DECAY}} = \frac{N_{\text{MAX}}}{R_{\text{NRZ}}}$$

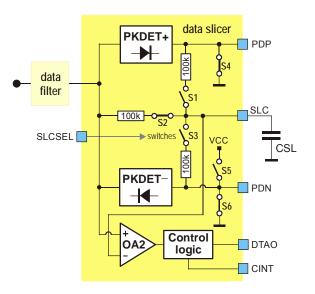


Fig. 6: Data path in averaging detection mode

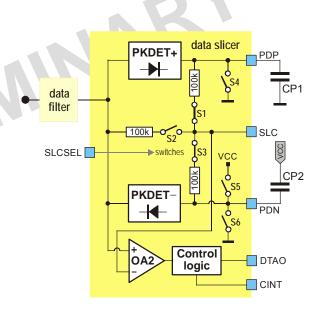


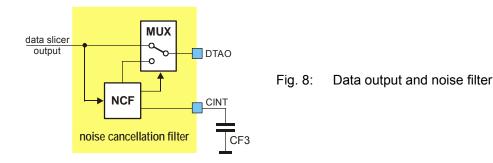
Fig. 7: Data path in peak detection mode

If the receiver is in shutdown mode and peak detection mode is selected then the peak detectors are disabled and the output of the positive peak detector (PDP) is connected to VEE (S4 is closed) and the output of the negative peak detector (PDN) is connected to VCC (S5 is closed). This guarantees the correct biasing of CP1 and CP2 during start-up



### 1.15 Data Output and Noise Cancellation Filter

The data output pin DTAO delivers the demodulated data signal that can be further processed by a noise cancellation filter (NCF). The NCF can be disabled if pin CINT is connected to VEE. In this case the multiplexer (MUX) connects the receiver output DTAO directly to the data slicer output.



The noise cancellation filter can suppress random pulses in the data output which are shorter than t<sub>min</sub>.

CF3 = 
$$15 \cdot 10^{-6} \cdot t_{\min} = \frac{15 \cdot 10^{-6}}{R_{NRZ}} = \frac{7.5 \cdot 10^{-6}}{R_{RZ}}$$

The NCF can also operate as a muting circuit for RF input signals that are below sensitivity level if the bandwidth of the preceding data filter is selected much higher than the bandwidth of the NCF. This would be the case if no RF signal is present.

In contrast to conventional muting (or squelch) circuits, this topology does not need the RSSI signal for level indication. The filtering process is done by means of an analogue integrator. The cut-off frequency of the NCF is set by the external capacitor connected to pin CINT. This capacitor  $C_{F3}$  should be set according to the maximum data rate. Below table provides some recommendations..

During receiver start-up a sequencer checks if pin CINT is connected to a capacitor or to ground. The maximum value of  $C_{F3}$  should not exceed 12nF. This defines the lowest data rate that can be processed if the noise cancellation filter is activated.

R <sub>RZ</sub> [kbit/s]	R <sub>NRZ</sub> [kbit/s]	C <sub>F3</sub> [nF]
0.6	1.2	12
1.2	2.4	6.8
1.6	3.2	4.7
2.4	4.8	3.3
3.3	6.6	2.2
4.8	9.6	1.5
6.0	12	1.2

In shutdown mode pin DTAO is set to Hi-Z state.



## 2 Frequency Planning

Because of the double conversion architecture that employs two mixers and two IF signals, there are four different combinations for injecting the LO1 and LO2 signals:

LO1 high side and LO2 high side:	receiving at f <sub>RF</sub> (high-high)
LO1 high side and LO2 low side:	receiving at f <sub>RF</sub> (high-low)
LO1 low side and LO2 high side:	receiving at f <sub>RF</sub> (low-high)
LO1 low side and LO2 low side:	receiving at f <sub>RF</sub> (low-low)

As a result, four different radio frequencies (RFs) could yield one and the same second IF (IF2). Fig. 9 shows this for the case of receiving at  $f_{RF}$ (high-high). In the example of Fig. 9, the image signals at  $f_{RF}$ (low-high) and  $f_{RF}$ (low-low) are suppressed by the bandpass characteristic provided by the RF front-end. The bandpass shape can be achieved either with a SAW filter (featuring just a couple of MHz bandwidth), or by the tank circuits at the LNA input and output (this typically yields 30 to 60MHz bandwidth). In any case, the high value of the first IF (IF1) helps to suppress the image signals at  $f_{RF}$ (low-high) and  $f_{RF}$ (low-low).

The two remaining signals at IF1 resulting from  $f_{RF}(high-high)$  and  $f_{RF}(high-low)$  are entering the second mixer MIX2. This mixer features image rejection with so-called single-sideband (SSB) selection. This means either the upper or lower sideband of IF1 can be selected. In the example of Fig. 9, LO2 high-side injection has been chosen to select the IF2 signal resulting from  $f_{RF}(high-high)$ .

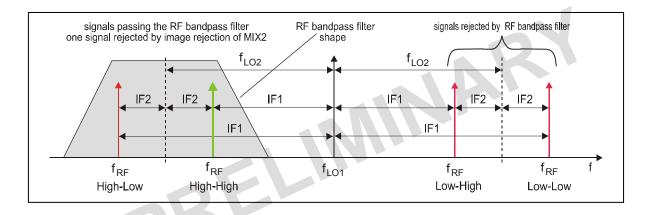


Fig. 9: The four receiving frequencies in a double conversion superhet receiver

It can be seen from the block diagram of Fig. 1 that there is a fixed relationship between the LO signal frequencies ( $f_{LO1}$ ,  $f_{LO2}$ ) and the reference oscillator frequency  $f_{RO}$ .

$$\mathbf{f}_{\text{LO1}} = \mathbf{N}_1 \cdot \mathbf{f}_{\text{LO2}} \qquad \qquad \mathbf{f}_{\text{LO2}} = \mathbf{N}_2 \cdot \mathbf{f}_{\text{RO}}$$

The IF2 frequency can be selected to 455kHz or 10.7MHz via the logic level at the IFSEL control pin. At the same time the output impedance of the 2<sup>nd</sup> mixer at pin MIXO is set according to the IF2 (please refer to pin description for details). Of course, also the operating frequency of the FSK demodulator (FSK DEMOD) is set accordingly.



### 2.1 Calculation of Frequency Settings

The receiver has two predefined receive frequency plans which can be selected by the RFSEL control pin. Depending on the logic level of RFSEL pin the sideband selection of the second mixer and the counter settings for N1 and N2 are changed accordingly.

RFSEL	Injection	f <sub>RFmin</sub> [MHz]	f <sub>RFmax</sub> [MHz]	N <sub>1</sub>	N <sub>2</sub>
0	high-low	300	470	4	6
1	low-high	610	930	2	12

The following table shows the relationships of several internal receiver frequencies for the two input frequency ranges.

f <sub>RF</sub> [MHz]	f <sub>IF1</sub>	f <sub>L01</sub>	f <sub>LO2</sub>	f <sub>RO</sub>
300 to 470	$\frac{f_{\rm RF} + N_1 f_{\rm IF2}}{N_1 - 1}$	$\frac{N_{1}(f_{RF}+f_{IF2})}{N_{1}-1}$	$\frac{f_{\text{RF}}+f_{\text{IF2}}}{N_1-1}$	$\frac{f_{\rm RF} + f_{\rm IF2}}{N_2(N_1 - 1)}$
610 to 930	$\frac{f_{\text{RF}} - N_1 f_{\text{IF2}}}{N_1 + 1}$	$\frac{N_{1}(f_{RF} + f_{IF2})}{N_{1} + 1}$	$\frac{f_{\text{RF}}+f_{\text{IF2}}}{N_1+1}$	$\frac{f_{\rm RF} + f_{\rm IF2}}{N_2(N_1 + 1)}$

Given IF2 is selectable at either 455kHz or 10.7MHz and the corresponding  $N_1$ ,  $N_2$  counter settings, above equations can be transferred into the following table.

#### IF2=455kHz

f <sub>RF</sub> [MHz]	f <sub>IF1</sub>	f <sub>L01</sub>	f <sub>LO2</sub>	f <sub>RO</sub>
300 to 470	$\frac{f_{RF} + 1.82MHz}{3}$	$\frac{4(f_{RF}+0.455MHz)}{3}$	$f_{RF} + 0.455MHz$	$\frac{f_{\text{RF}} + 0.455 MHz}{18}$
610 to 930	$\frac{f_{RF} - 0.91MHz}{3}$	$\frac{2(f_{\rm RF}+0.455\rm MHz)}{3}$	3	$\frac{f_{\text{RF}} + 0.455 MHz}{36}$

#### IF2=10.7MHz

f <sub>RF</sub> [MHz]	f <sub>IF1</sub>	f <sub>L01</sub>	f <sub>LO2</sub>	f <sub>RO</sub>
300 to 470	$\frac{f_{RF} + 42.8MHz}{3}$	$\frac{4(f_{RF}+10.7MHz)}{3}$	f <sub>RF</sub> +10.7MHz	$\frac{f_{\text{RF}} + 10.7 MHz}{18}$
610 to 930	$\frac{f_{RF} - 21.4MHz}{3}$	$\frac{2(f_{RF} + 10.7MHz)}{3}$	3	$\frac{f_{\text{RF}} + 10.7 MHz}{36}$

## 2.2 Standard Frequency Plans

IF2 = 455kHz					
RFSEL	f <sub>RF</sub> [MHz]	f <sub>IF1</sub> [MHz]	f <sub>LO1</sub> [MHz]	f <sub>LO2</sub> [MHz]	f <sub>RO</sub> [MHz]
0	315	105.6067	420.6067	105.1517	17.525278
0	433.92	145.2467	579.1667	144.7917	24.131944
1	868.3	289.1300	579.1700	289.5850	24.132083
	915	304.6967	610.3033	305.1517	25.429306

#### IF2 = 10.7MHz

RFSEL	f <sub>RF</sub> [MHz]	f <sub>IF1</sub> [MHz]	f <sub>L01</sub> [MHz]	f <sub>LO2</sub> [MHz]	f <sub>RO</sub> [MHz]
0	315	119.2667	434.2667	108.5667	18.094444
U	433.92	158.0667	592.8267	148.2067	24.701111
1	868.3	282.3000	586.0000	293.0000	24.416667
	915	297.8667	617.1333	308.5667	25.713889

## 2.3 433/868MHz Frequency Diversity

The receiver's multi-band functionality can be used to operate at two different frequency bands just by changing the logic level at pin RFSEL and without changing the crystal. This feature is applicable for common use of the 433 and 868MHz bands. Below table shows the corresponding frequency plans.

#### IF2 = 455kHz

RFSEL	f <sub>RF</sub> [MHz]	f <sub>IF1</sub> [MHz]	f <sub>L01</sub> [MHz]	f <sub>LO2</sub> [MHz]	f <sub>RO</sub> [MHz]	
0	433.9225	145.2483	579.17	144.7925	24.132083	
1	868.3	289.1300	579.17	289.5850	24.132005	



# 3 Pin Definitions and Descriptions

Pin No.	Name	I/O Type	Functional Schematic	Description
3	LNAO1	analog output		LNA output 1
1	LNAI1	analog input		LNA input 1
2	VEE	ground		negative supply voltage
4	MIXP	analog input		MIX1 positive input
5	MIXN	analog input		MIX1 negative input
6	LNAO2	analog output		LNA output 2
8	LNAI2	analog input		LNA input 2
7	VEE	ground		negative supply voltage
9	VCC	supply		positive supply voltage
10	MIXO	analog output	MIXO 10 VCC VCC VCC VCC VCC VCC VCC VC	mixer 2 output, about 150Ω at 10.7MHz and 670 Ω at 455kHz, resp.
11	VEE	ground		negative supply voltage
12	IFAP	analog input		IF amplifier positive input
13	IFAN	analog input		IF amplifier negative input



Pin No.	Name	I/O Type	Functional Schematic	Description
14	MODSEL	CMOS input	MODSEL 14 VCC VCC VCC VCC VCC VCC VCC VC	modulation select input
15	SLCSEL	CMOS input		slicer mode select input
16	DF2	analog I/O		data filter connection 2
17	DF1	analog I/O		data filter connection 1
18	DFO	analog output		data filter output
19	SLC	analog input	SLC 19 VCC 100k 100k VEE	slicer reference input
20	PDP	analog output		peak detector positive output



Pin No.	Name	I/O Type	Functional Schematic	Description
21	PDN	analog output		peak detector negative output
22	VCC	supply		positive supply voltage
23	CINT	analog input		capacitor for noise cancella- tion filter pin must be connected to ground if noise cancellation filter is not used
24	RSSI	analog output	RSSI 24 VEE VEE	receive signal strength indication
25	ROI	analog input		reference oscillator input
26	TEST	CMOS input	not used connect to ground	test pin
27	IFSEL	CMOS input	IFSEL 27 VCC VCC VCC VCC VCC VCC VCC VCC VCC VC	IF select input
28	CLKO	CMOS output		clock output connect pull-up resistor to activate clock



Pin No.	Name	I/O Type	Functional Schematic	Description
29	DTAO	CMOS output		data output
30	ENRX	CMOS input		enable RX mode control
31	RFSEL	CMOS input	RFSEL 31 VCC VCC R 400 VEE VEE	receive frequency select input
32	LNASEL	CMOS input	LNASEL 400 32 VEE	LNA select input
		PR		



## 4 Technical Data

## 4.1 Absolute Maximum Ratings

Operation beyond absolute maximum ratings may cause permanent damage of the device.

Parameter	Symbol	Condition	Min	Max	Unit
Supply voltage	V <sub>cc</sub>		0	7	V
Input voltage	V <sub>IN</sub>		-0.3	V <sub>CC</sub> +0.3	V
Storage temperature	T <sub>STG</sub>		-55	150	°C
Junction temperature	TJ			150	°C
Thermal Resistance	$R_{thJA}$			22	K/W
Power dissipation	P <sub>diss</sub>			0.12	W
Electrostatic discharge	$V_{\text{ESD}}$	HBM according to MIL STD 833D, method 3015.7	±1		kV

## 4.2 Normal Operating Conditions

Parameter	Symbol	Condition	Min	Max	Unit		
Supply voltage	V <sub>cc</sub>		2.1	5.5	V		
Operating temperature	T <sub>A</sub>		-40	125	°C		
Input low voltage (CMOS)	$V_{IL}$	ENRX, SEL pins		0.3*V <sub>CC</sub>	V		
Input high voltage (CMOS)	V <sub>IH</sub>	ENRX, SEL pins	0.7*V <sub>CC</sub>		V		
Input frequency range	f <sub>RF</sub>	RFSEL=0	300	470	MHz		
	IRF	RFSEL=1	610	930			
First IF range	f <sub>IF1</sub>	RFSEL=0	100	170	MHz		
r list li range	<b>1</b> ⊩1	RFSEL=1	200	310	MHZ		
Second IF range f <sub>IF</sub>			0.4	11	MHz		
LO1 range (VCO frequency)	f <sub>LO1</sub>	$f_{LO1} = 24^* f_{REF}$	400	640	MHz		
LO2 range	$f_{LO2}$	RFSEL=0, f <sub>LO2</sub> = f <sub>LO1</sub> / 4	100	160	MHz		
		RFSEL=1, f <sub>LO2</sub> = f <sub>LO1</sub> / 2	200	320			
XOSC frequency	$f_{REF}$	set by the crystal	16	27	MHz		
CLKO frequency	$f_{CLK}$	f <sub>CLK</sub> = f <sub>REF</sub> / 8	2.0	3.375	MHz		
FSK deviation	$\Delta f$	IFSEL=0	±2	±10	kHz		
		IFSEL=1	±10	±100			
Data rate ASK	R <sub>ASK</sub>	bi-phase code		50	kbps		
Data fate ASK	I ASK	NRZ		100	кора		
		bi-phase code, IFSEL=0		5			
Data rate FSK	D	NRZ, IFSEL=0		10	kbps		
	R <sub>FSK</sub>	bi-phase code, IFSEL=1		50	ruha		
		NRZ, IFSEL=1		100			



## 4.3 DC Characteristics

all parameters under normal operating conditions, unless otherwise stated; typical values at  $T_A$ = 23 °C and  $V_{CC}$  = 3 V, all parameters based on test circuits as shown Fig. 10 to Fig. 11

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Operating Currents						
		ENRX=0, T <sub>A</sub> = 85°C		50	200	nA
Shutdown current	I <sub>SDN</sub>	ENRX=0, T <sub>A</sub> = 125°C			4	μA
Supply current reference oscillator	I <sub>RO</sub>	ENRX=1, t < t <sub>onRO</sub>		1.5		mA
Supply current, FSK IF2= 455kHz	I <sub>FSK1</sub>	ENRX=1, MODSEL= 1 IFSEL=0, SLCSEL=0 LNASEL=0 or 1		7.0		mA
Supply current, FSK IF2= 10.7MHz	I <sub>FSK2</sub>	ENRX=1, MODSEL= 1 IFSEL=1, SLCSEL=0 LNASEL=0 or 1		7.5		mA
Supply current, ASK IF2= 455kHz	I <sub>ASK1</sub>	ENRX= 1, MODSEL= 0 IFSEL=0, SLCSEL=0 LNASEL=0 or 1		6.6		mA
Supply current, ASK IF2= 10.7MHz	I <sub>ASK2</sub>	ENRX= 1, MODSEL= 0 IFSEL=1, SLCSEL=0 LNASEL=0 or 1		7.1		mA
Digital Pin Characteristics (exce	pt of LNAS	EL)				
Input low voltage (CMOS)	V <sub>IL</sub>	ENRX, SEL pins			0.3*V <sub>CC</sub>	V
Input high voltage (CMOS)	V <sub>IH</sub>	ENRX, SEL pins	$0.7*V_{CC}$			V
Pull down current ENRX pin	I <sub>PDEN</sub>	ENRX=1	2	8	30	μA
Low level input current ENRX pin	I <sub>INLEN</sub>	ENRX=0			1	μA
High level input current	IINHSEL	SEL pins			1	μA
Low level input current	I <sub>INLSEL</sub>	SEL pins			1	μA
LNASEL Pin Characteristics						
Input voltage LNA1 active	V <sub>LNASEL1</sub>	ENRX=1			$0.1*V_{CC}$	V
Input voltage LNA2 active	V <sub>LNASEL2</sub>	ENRX=1	0.9*V <sub>CC</sub>			V
DTAO Pin Characteristics						
Output low voltage	V <sub>OL</sub>	DTAO pin, I <sub>SINK</sub> = 600μA			0.3*V <sub>CC</sub>	V
Output high voltage	V <sub>OH</sub>	DTAO pin, I <sub>SOURCE</sub> = 600µA	0.7*V <sub>CC</sub>			V



## 4.4 AC System Characteristics

all parameters under normal operating conditions, unless otherwise stated; typical values at  $T_A$ = 23 °C and  $V_{CC}$  = 3 V, all parameters based on test circuits as shown Fig. 11

Parameter			Sym- bol	Condition			Min	Тур	Max	Unit
Receive Ch	aracteristics	5								
Input Sensit	ivity 1)			MODSEL	IFSEL	RFSEL		_		
		315MHz	P <sub>min1</sub>			0		-109		
FSK		433MHz	P <sub>min2</sub>	1	1	U		-108		dBm
1 SK		868MHz	P <sub>min3</sub>	1	1	1		-106		ubiii
	wide band	915MHz	P <sub>min4</sub>			I		-104		
	180kHz BW	315MHz	$P_{min5}$			0		-113		– dBm
ASK		433MHz	P <sub>min6</sub>	0	1			-113		
ASK		868MHz	P <sub>min7</sub>			1		-111		
		915MHz	P <sub>min8</sub>			I		-109		
		315MHz	P <sub>min9</sub>		0	0		-114		- dBm
FSK	narrow band	433MHz	P <sub>min10</sub>	- 1				-112		
FSK	20kHz BW	868MHz	P <sub>min11</sub>			1		-111		
		915MHz	P <sub>min12</sub>					-109		
Maximum input signal – FSK			P <sub>max,</sub> FSK	MODSEL=1				-10		dBm
Maximum input signal – ASK			P <sub>max,</sub> ASK	MODSEL=0, M>20dB				-10		dBm
Spurious emission			P <sub>spur</sub>						-54	dBm
Image rejec	tion 1 <sup>st</sup> IF		IR <sub>1</sub>	w/o SAW filter				20		dB
Image reject	tion 2 <sup>nd</sup> IF		IR <sub>2</sub>					25		dB

1) at 4kbps NRZ, BER  $\leq 3.10^{-3}$ , peak detector data slicer, LNASEL = 0 or 1

WB:  $\Delta f = \pm 20 \text{kHz}$ 

NB:  $\Delta f = \pm 5 kHz$ 



Parameter	Symbol	Condition	Min	Тур	Max	Unit
LNA Parameters						
Voltage gain	G <sub>LNA</sub>	depends on external LC tank		18		dB
Mixer Section Parameters						
Mixer output impedance	Z <sub>MIXO</sub>	IFSEL=0 IFSEL=1		1500 330		Ω
Voltage conversion gain	G <sub>MIX</sub>	with CERFIL between MIXO and IFAP		25		dB
Input referred 3 <sup>rd</sup> order intercept point	IIP3	with CERFIL between MIXO and IFAP		-40		dBm
IF Amplifier / RSSI						
Operating frequency	f <sub>IFA</sub>		0.4		11	MHz
RSSI dynamic range	DR <sub>RSSI</sub>			70		dB
RSSI slope	S <sub>RSSI</sub>			20		mV/dB
FSK Demodulator						
Input frequency range	f <sub>DEM</sub>	IFSEL=0		455		kHz
input frequency range	IDEM	IFSEL=1		10.7	7	MHz
Carrier acceptance range	$\Delta f_{DEM}$	IFSEL=0		±20		kHz
Carrier acceptance range		IFSEL=1		±400		KI IZ
Demodulator sensitivity	S <sub>DEM</sub>	IFSEL=0		50		mV/
	ODEM	IFSEL=1		5		kHz
Baseband Data Path						
Data filter bandwidth	B <sub>DF</sub>	depending on CF1, CF2			100	kHz
Peak detector load current	I <sub>PKD</sub>			500		μA
Start-up Parameters						
Reference oscillator start-up time	t <sub>onRO</sub>	depending on crystal parameters		350	650	μs
Sequencer time	t <sub>SEQ</sub>	5504 / f <sub>REF</sub>	200	250	350	μs
Receiver start-up time	t <sub>onRX</sub>	t <sub>onRO</sub> + t <sub>SEQ</sub>		0.6	1	ms
Frequency Stability						
Frequency pulling by supply voltage	$df_{VCC}$				±3	ppm/V



## 4.5 External Components

Parameter Symbol		Condition	Min	Max	Unit				
Crystal Parameters									
Crystal frequency	f <sub>0</sub>	fundamental mode, AT	16	27	MHz				
Load capacitance	CL		10	15	pF				
Static capacitance	C <sub>0</sub>			5	pF				
Series resistance	R <sub>1</sub>			60	Ω				
Noise Cancellation Filter									
Integrator capacitor	CF3	depends on data rate		12	nF				
Clock Output									
Pull-up resistor	RCL		600		Ω				
Load capacitance	CL			50	pF				



## 5 Test Circuits

## 5.1 Dual-Channel Application Circuit

- for antenna-diversity applications
- for frequency-diversity applications

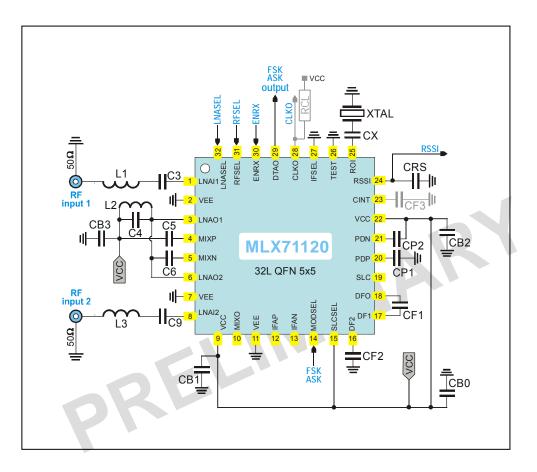


Fig. 11: Dual-channel circuit schematic, peak detectors activated



# MLX71120 300 to 930MHz FSK/FM/ASK Receiver

## 5.1.1 Test Circuit Component List of Figures 11

Part	Size	Value @ 315 MHz	Value @ 433.92 MHz	Value @ 868.3 MHz	Value @ 915 MHz	Tol.	E	Description	
C3	0603	100 pF	100 pF	100 pF	100 pF	±5%	LNA input filte	ring capacitor	
C4	0603	4.7 pF	3.9 pF	2.2 pF	1.5 pF	±5%	LNA output tar	nk capacitor	
C5	0603	100 pF	100 pF	100 pF	100 pF	±5%	MIX1 positive	input matching capacitor	
C6	0603	100 pF	100 pF	100 pF	100 pF	±5%	MIX1 negative	input matching capacitor	
C9	0603	100 pF	100 pF	100 pF	100 pF	±5%	LNA input filter	ring capacitor	
CB0	0805	33 nF	33 nF	33 nF	33 nF	±10%	decoupling cap	pacitor	
CB1	0603	330 pF	330 pF	330 pF	330 pF	±10%	decoupling cap	pacitor	
CB2	0603	330 pF	330 pF	330 pF	330 pF	±10%	decoupling cap	pacitor	
CB3	0603	330 pF	330 pF	330 pF	330 pF	±10%	decoupling cap	pacitor	
CF1	0603	680 pF	680 pF	680 pF	680 pF	±10%	data low-pass filter capacitor, for data rate of 4 kbps NRZ		
CF2	0603	330 pF	330 pF	330 pF	330 pF	±10%	data low-pass filter capacitor, for data rate of 4 kbps NRZ		
CF3	0603		value according		lead	±10%	optional capacitor for noise cancellation		
CIF	0603	1 nF	1 nF	1 nF	1 nF	±10%	IFA feedback capacitor		
CP1	0603	33 nF	33 nF	33 nF	33 nF	±10%	positive PKDET capacitor, for data rate of 4 kbps NRZ		
CP2	0603	33 nF	33 nF	33 nF	33 nF	±10%	negative PKDET capacitor, for data rate of 4 kbps NRZ		
CRS	0603	1 nF	1 nF	1 nF	1 nF	±10%	RSSI output lo for data rate of	w pass capacitor, f 4 kbps NRZ	
CSL	0603	100 nF	100 nF	100 nF	100 nF	100/	data slicer cap	pacitor,	
COL	0603		for averaging dete	ection mode only		±10%	for data rate of	f 4 kbps NRZ	
СХ	0603	27 pF	27 pF	27 pF	27 pF	±5%	crystal series of	capacitor	
L1	0603	56 nH	27 nH	0 Ω	0 Ω	±5%	matching indu	ctor	
L2	0603	27 nH	15 nH	3.9 nH	3.9 nH	±5%	LNA output tar	nk inductor	
L3	0603	56 nH	27 nH	0Ω	0 Ω	±5%	matching indu	ctor	
RCL	0603	3.3 k $\Omega$	3.3 kΩ	3.3 kΩ	3.3 kΩ	±5%	optional CLK of to clock output	output resistor, t signal generated	
CER	SMD 3.45x3.1		SFECF10 B <sub>3dB</sub> = 1				IF2=10.7MHz		
FIL	SMD 6.5x6.0	CFUKG455KD4A B <sub>6dB</sub> = 20 kHz					IF2=455kHz	from Murata, or equivalent part	
XTAL	SMD	18.094444 MHz 17.525278	24.701111 MHz 24.131944	24.416667 MHz 24.132083	25.713889 MHz 25.429306		IF2=10.7MHz	crystal from Telcona,	
ATAL	5x3.2	MHz	MHz	MHz	25.429300 MHz	-	IF2=455kHz	or equivalent part	
			±20ppm cal., ±	30ppm temp.					

Note:	NIP – not in place, may be used optionally
-------	--



## 6 Package Description



The device MLX71120 is RoHS compliant.

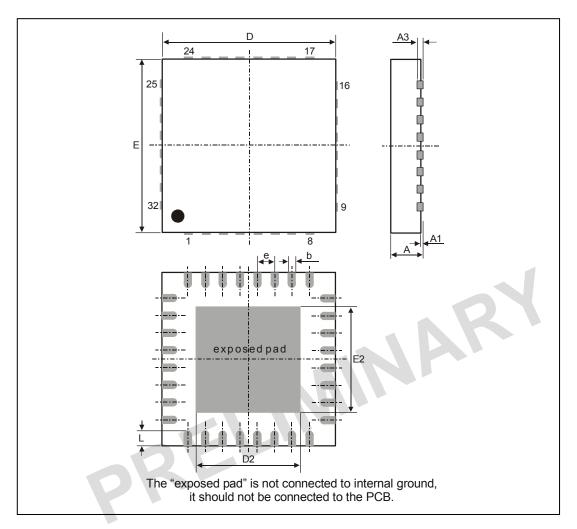


Fig 12: 32L QFN 5x5 Quad

all Dime	all Dimension in mm										
	D	Е	D2	E2	Α	A1	<b>A3</b>	L	е	b	
min	4.75	4.75	3.00	3.00	0.80	0	0.20	0.3	0.50	0.18	
max	5.25	5.25	3.25	3.25	1.00	0.05	0.20	0.5	0.50	0.30	
all Dime	all Dimension in inch										
min	0.187	0.187	0.118	0.118	0.0315	0	0.0079	0.0118	0.0197	0.0071	
max	0.207	0.207	0.128	0.128	0.0393	0.002		0.0197		0.0118	

## 6.1 Soldering Information

• The device MLX71120 is qualified for MSL3 with soldering peak temperature 260 deg C according to JEDEC J-STD-20



## 7 Reliability Information

This Melexis device is classified and qualified regarding soldering technology, solderability and moisture sensitivity level, as defined in this specification, according to following test methods:

Reflow Soldering SMD's (<u>Surface Mount Devices</u>)

- IPC/JEDEC J-STD-020
- "Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices (classification reflow profiles according to table 5-2)"
- EIA/JEDEC JESD22-A113
- "Preconditioning of Nonhermetic Surface Mount Devices Prior to Reliability Testing (reflow profiles according to table 2)"

Wave Soldering SMD's (Surface Mount Devices) and THD's (Through Hole Devices)

- EN60749-20
- "Resistance of plastic- encapsulated SMD's to combined effect of moisture and soldering heat"
- EIA/JEDEC JESD22-B106 and EN60749-15
- "Resistance to soldering temperature for through-hole mounted devices"

Iron Soldering THD's (<u>Through Hole Devices</u>)

- EN60749-15
- "Resistance to soldering temperature for through-hole mounted devices"

Solderability SMD's (Surface Mount Devices) and THD's (Through Hole Devices)

- EIA/JEDEC JESD22-B102 and EN60749-21
- "Solderability"

For all soldering technologies deviating from above mentioned standard conditions (regarding peak temperature, temperature gradient, temperature profile etc) additional classification and qualification tests have to be agreed upon with Melexis.

The application of Wave Soldering for SMD's is allowed only after consulting Melexis regarding assurance of adhesive strength between device and board.

Melexis is contributing to global environmental conservation by promoting **lead free** solutions. For more information on qualification of **RoHS** compliant products (RoHS = European directive on the Restriction Of the Use of Certain Hazardous Substances) please visit the quality page on our website:

http://www.melexis.com/quality\_leadfree.aspx

## 8 ESD Precautions

Electronic semiconductor products are sensitive to Electro Static Discharge (ESD). Always observe Electro Static Discharge control procedures whenever handling semiconductor products.



## Your Notes



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